Applicant(s)/Patent Under Application/Control No. Reexamination 10/740,465 BAEK ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 2629 Seokyun Moon **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY * US-6,377,251 04-2002 345/204 Takasu et al. Α US-В US-С US-D US-E US-F US-G USн US-US-US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R s Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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